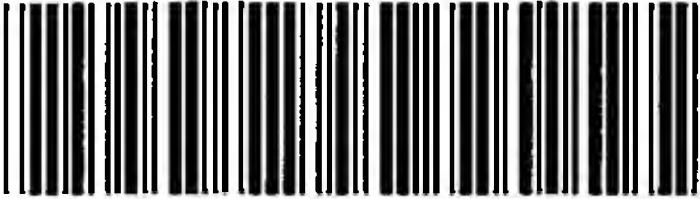


<div>Search Notes</div> <div></div>	Applicati n/Control N .	Applicant(s)/Patent under Reexamination	
	10/710,740	TSUEI ET AL.	
	Examiner	Art Unit	
	Thien M. Le	2876	

SEARCHED			
Class	Subclass	Date	Examiner
235	380		
	449		
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	375		
	379		
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	382.5		
705	1,54		
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	26,67		
709	204,206		
	248	6/22/2006	LTM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	6/22/2006	LTM